

1 **Variety of stylolites morphologies and statistical characterization of the**
2 **amount of heterogeneities in the rock**

3

4

5 **Alexandre Brouste**

6 Laboratoire de Modélisation et de Calcul, Université Joseph Fourier, BP 53, 38041 Grenoble, France

7 **François Renard***8 Laboratoire de Géophysique Interne et Tectonophysique, CNRS, Université Joseph Fourier, BP 53, 38041
9 Grenoble, France & Physics of Geological Processes, University of Oslo, Norway10 **Jean-Pierre Gratier**11 Laboratoire de Géophysique Interne et Tectonophysique, Université Joseph Fourier, BP 53, 38041 Grenoble,
12 France13 **Jean Schmittbuhl**14 UMR 7516, Institut de Physique du Globe de Strasbourg, 5 rue René Descartes, F-67084 Strasbourg cedex,
15 France

16

17 *Corresponding author:

18 francois.renard@ujf-grenoble.fr, Phone +33 476 82 80 88, Fax; +33 476 82 81 01

19 **Abstract.** The surface roughness of several stylolites in limestones was measured using
20 high resolution laser profilometry. The 1D signals obtained were statistically analyzed to
21 determine the scaling behavior and calculate a roughness exponent, also called Hurst
22 exponent. Statistical methods based on the characterization of a single Hurst exponent
23 imply strong assumptions on the mathematical characteristics of the signal: the derivative of
24 the signal (or local increments) should be stationary and have finite variance. The analysis
25 of the measured stylolites show that these properties are not always verified simultaneously.
26 The stylolite profiles show persistence and jumps and several stylolites are not regular, with
27 alternating regular and irregular portions. A new statistical method is proposed here, based
28 on a non-stationary but Gaussian model, to estimate the roughness of the profiles and
29 quantify the heterogeneity of stylolites. This statistical method is based on two parameters:
30 the local roughness (H) which describes the local amplitude of the stylolite, and the amount
31 of irregularities on the signal (μ), which can be linked to the heterogeneities initially present
32 in the rock before the stylolite formed. Using this technique, a classification of the stylolites
33 in two families is proposed: those for which the morphology is homogeneous everywhere
34 and those with alternating regular and irregular portions.

35 *Key words:* stylolites, roughness, scaling analysis, heterogeneity

36

37 1. Introduction

38 The geometrical characterization of rough profiles or surfaces is a widespread problem in
 39 various geological examples such as erosion patterns (Dunne, 1980; Cerasi et al., 1995),
 40 multiphase fluid percolation in porous rocks (Rubio et al., 1989), fractures (Schmittbuhl et
 41 al., 1993), or stylolites (Renard et al., 2004). In these studies, the scaling behavior of
 42 various data sets was investigated, showing that the statistics at one scale could be
 43 extrapolated to another scale using a power law relationship.

44 For a self-affine function $h(x)$, a scaling relationship is defined when the signal follows a
 45 power law relationship under a dilation of a factor λ

$$46 \quad h(\lambda x) = \lambda^D h(x) \quad (1)$$

47 where x is the spatial coordinate and h is a scalar field, λ is the scaling scalar, and D is the
 48 scaling exponent.

49 Applying this property to 1D discrete signals, involves working on the increments $\delta h(x)$ of
 50 the function h . The self-similar property of a 1D data set $h(x)$ emerges when the increments
 51 of the signal follows

$$52 \quad \delta(h(\lambda x)) = \lambda^H \delta(h(x)) \quad (2)$$

53 where H is the so-called Hurst exponent (Feder, 1988; Meakin, 1998).

54 This scaling approach is based on two assumptions on the mathematical properties of the
 55 signal. First, increments of the signal have finite variance distribution and, second they are
 56 stationary, which means that the statistics are independent of the position along the signal.
 57 In the case of a signal with increments that follow a Gaussian distribution (that has a finite
 58 variance by definition), the roughness of the signal can be deduced from the scaling
 59 exponent.

60 For a function $h(x)$ with the property:

61 $|h(x) - h(y)| \leq C|x - y|^{H_0}$, (3)

62 where x and y are two different points along the signal and C is a constant, H_0 is defined as
63 the Hölder exponent (Daubechies, 1992). When the increments of a signal are Gaussian and
64 stationary, the Hölder exponent is equal to the Hurst exponent.

65 In this contribution, the assumption of Gaussian stationary increments of several 1D data
66 sets is tested, based on roughness measurements of various stylolites in limestones. We
67 show that these profiles do not verify the Gaussian stationary increments property, and we
68 propose a new technique to characterize the statistics of these signals by introducing two
69 parameters: the *localized* roughness exponent H , and a second parameter μ , which
70 characterizes the quantity of irregularities in the system at all scales. Applied to stylolites,
71 this parameter can be used to quantify the degree of heterogeneity in the rock initially
72 present before the stylolitization process. We also show that heterogeneities have an effect
73 only above a millimeter scale.

74 We first present some examples showing how heterogeneities determine the location of
75 some stylolite peaks. Then the two-parameter statistical description of stylolite roughness is
76 used to help characterize such heterogeneities.

77 **2. The roughness of stylolites**

78 *2.1. Self-similar scaling of stylolites*

79 Stylolites are rough surfaces that develop by stress-enhanced dissolution in crustal rocks
80 (Dunnington, 1954; Park and Schot, 1968; Bathurst, 1971; Bayly, 1986). Anticrack models
81 have been proposed to describe their initial stage of nucleation and propagation as a flat
82 interface (Fletcher and Pollard, 1981; Koehn et al., 2003; Katsman and Aharonov, 2006).
83 With time, the stylolites roughen and acquire their typical wavy geometry (Figures 1, 2).

84 The wide range of morphological geometries of such surfaces makes them difficult to
 85 characterize using a simple scaling approach. However, it has been shown that stylolites
 86 have self-similar scaling properties (Karcz and Scholz, 2002; Renard et al., 2004;
 87 Schmittbuhl et al., 2004). These studies are based on the assumption that the morphological
 88 statistics of the stylolites do not vary laterally along the plane of the interface.

89 Here, the topography of stylolites in limestones was measured using high-resolution laser
 90 profilometers that acquire (1+1)D roughness profiles (Figure 2). Some stylolites were split
 91 open to reveal the complex 2D geometry of their surface. Using this method, described in
 92 Renard et al., (2004), (2+1)D maps of stylolite roughness can be obtained with an accuracy
 93 of up to 0.003 mm, on a regular grid of 0.03 to 0.125 mm depending on the kind of
 94 profilometer used. The (2+1)D maps were built by combining (1+1)D profiles on a square
 95 grid with a constant discretization interval. For each stylolite surface, the result is a (2+1)D
 96 height field from which the mean plane was removed by a least-square method.

97 Using these data, stylolitic 1D profiles were found to show two different self-affine regimes
 98 at large and small length scales (Figure 3). Two signal processing techniques were used: the
 99 Fourier Power Spectrum (FPS) and the Averaged Wavelet Coefficient (AWC).

100 FPS decomposition techniques are standard tools used to characterize the scaling behaviour
 101 of stationary increments signals (Kahane and Lamarié-Rieusset, 1998). Assuming finite
 102 variance stationary increments of a signal, the Hurst exponent H (eq. 2) can be deduced
 103 from the power-law behaviour of the Fourier Power Spectrum with

$$104 \quad FPS(k) \propto k^{-1-2H} \quad (4)$$

105 where k is the wave number, the inverse of the wavelength (Barabási and Stanley, 1995).

106 Wavelet series (or wavelet decompositions) constitute a powerful tool for processing
 107 signals in which different scales are combined (Meyer and Roques, 1993). Various signals
 108 can be reconstructed knowing the coefficients of their wavelet decomposition, and for

109 compactly supported wavelets (Daubechies, 1992) any 1D profile, $h(x)$, can be decomposed
 110 into a wavelet series having the following summation:

$$111 \quad h(x) = \sum_{j=0}^{+\infty} \sum_{i=0}^{2^j-1} c_{i,j} \psi(2^j x - i) \quad (5)$$

112 where $c_{j,i}$ are the wavelet coefficients indexed by (j,i) and ψ is the so-called mother
 113 wavelet (generating all the wavelets by expansion of a factor 2^j and by a translation i).

114 Using this method, the self-similar behaviour of a signal emerges as the average wavelet
 115 coefficient AWC satisfies:

$$116 \quad AWC(l) \propto l^{H+0.5}, \quad (6)$$

117 where l is the spatial wavelength (Simonsen *et al.*, 1998).

118 These two techniques provide a scaling relationship and the Hurst exponent is directly
 119 related to the slope of the spectra. In the case of a signal with Gaussian and stationary
 120 increments, the Hölder exponent is equal to the Hurst exponent.

121 In stylolites, these two signal processing techniques give the same Hurst exponent (eq. 2),
 122 $H = 0.5$ for the large length scales and $H = 1.1$ for small length scales (Figure 3, see also
 123 Renard *et al.*, 2004).

124 The measurements also show that a sharp cross-over length scale close to the millimeter
 125 scale separates the two regimes. This characteristic length scale has been interpreted as a
 126 crossover length emerging from the competition between two forces: surface tension
 127 dominates at small wavelengths, whereas elastic interactions dominate at large wavelengths
 128 (Renard *et al.*, 2004; Schmittbuhl *et al.*, 2004).

129 Using the same data sets, it can also be shown that a stylolite can be wavy at one point and
 130 rather flat at another point (Figure 2), suggesting that the statistical properties vary along
 131 the profiles. Therefore, the Gaussian stationary increments hypothesis must be called into

132 question. This spatial variation in statistical properties along a single stylolite is not
133 accounted for in current models of stylolite roughening.

134 *2.2. Heterogeneities along stylolites*

135 Various examples both from nature and experiments show that heterogeneities in rocks help
136 either to localize dissolution pits or to deflect the dissolution surface along a single stylolite
137 at all scales. [Figure 4a](#) shows experimental microstylolites along quartz grains ([Gratier et
138 al., 2005](#)). Dissolution pits ([Figure 4b](#)) are systematically located at the bottom of each
139 conical-shaped stylolite structure. Due to the fit of the two opposite grain surfaces, the pits
140 of the lower grain stylolite surface are located just in front of the stylolitic peak of the upper
141 grain and vice versa. The explanation is that pits develop at intersections of crystal
142 dislocations with the grain surface and determine the stylolite peak location.

143 [Figure 4c](#) shows the indenting of a mineral (quartz) by another mineral (mica). In this case,
144 the mica grains along the dissolution surface are responsible for the local dissolution peaks.
145 Mica distribution determines the location of the peaks location.

146 The same geometry may be observed along columnar stylolites in limestones ([Figure 4d](#)).
147 However, the interpretation is different as the two parts of the rock have the same
148 composition. In this case, the geometry of the columnar stylolite is probably determined by
149 preexisting micro-fractures as is clearly the case in the example shown in [Figure 4e](#) where a
150 fracture controls the shape of the peak. Finally, [Figure 4f](#) shows several dissolution seams
151 that are deflected by hard objects: pyrite (black) or quartz pressure shadows (white). In this
152 case, the hard objects located in the dissolution plane deflect it, thereby contributing to
153 roughening of the dissolution surface.

154 All these examples show that the location of some stylolite peaks is not purely random but
155 rather partially controlled by the distribution of heterogeneities. The statistical properties of
156 stylolites should depend on the distribution of these heterogeneities, and therefore vary in

157 space along a single stylolite. It would appear relevant to integrate the presence of non-
158 uniformly distributed heterogeneities at all scales in the modeling of stylolites and test their
159 potential effect on the final geometry.

160 **3. A two-parameter statistical description of the roughness of 1D stylolite** 161 **profiles**

162 The wide range of morphologies of stylolites (Figure 1) and the alternating smooth and
163 irregular portions of the same stylolite (Figures 2, 5a), suggests that the Gaussian stationary
164 increments assumption should be tested. In this section we show that it is not possible to
165 obtain all stylolite morphologies from a single parameter scaling relationship (e. g. a Hurst
166 exponent).

167 Figure 5b represents the increments of a 1D stylolite. These increments are calculated as the
168 height difference between two successive points, and therefore represent a first order
169 derivative of the original signal of Figure 5a. In this incremental signal, the existence of
170 many large jumps and long tails in the histogram (Figure 5c) differentiate the signal from a
171 synthetic fractional Gaussian noise signal (Figure 5h). Therefore, the Gaussian self-similar
172 stationary increments property can be excluded for stylolite signals and a simple scaling
173 relationship using a single Hurst exponent is not sufficient to explain the measured signals.
174 The following section proposes a new technique that can accommodate the large jumps of
175 Figure 5b so that it can be applied to stylolites. This analysis has been tested on all the
176 available stylolites surfaces, and show similar properties.

177 *3.1. The Simple Branching Process Wavelet Series method*

178 Mathematicians commonly use two different techniques to deal with the large jumps
179 similar to those shown in Figure 5b. The first technique is to select a non-Gaussian self-
180 similar stationary increment model with infinite variance, also called stable Lévy motion

181 (Samorodnitsky and Taqqu, 1994). Stable Lévy motions contain two parameters: the
 182 frequency of the jumps and the average size of these jumps. Applied to stylolites,
 183 microfractures densities in the rocks can be associated with the frequency of jumps for
 184 instance and estimated by specific methods. However, in such models, the roughness
 185 cannot be identified from the scaling relationship because the roughness and the scaling
 186 exponents are not similar. The Lévy models are avoided in the following discussion.
 187 The second technique is a non-stationary Gaussian model with scaling properties, where
 188 the roughness can be estimated. According to Samorodnitsky and Taqqu (1994), neither of
 189 these techniques is superior to the other.. In the following section, the non-stationary
 190 Gaussian model is used and referred to as the Simple Branching Process Wavelet Series (in
 191 short SBPWS).

192 3.2. Construction of SBPWS profiles in one dimension

193 Simple Branching Processes (also called Galton-Watson processes, see Harris, 1969) are
 194 stochastic trees built by an incremental branching process at all scales. In the case of Simple
 195 Branching Process Wavelet Series (SBPWS), each node of the tree has the same probability
 196 of having either one or two branches (see Figure 6a). In the following, $1 <$
 197 $\mu < 2$ corresponds to the average number of sons at each node. For a node of the tree, $(2-$
 198 $\mu)$ represents the probability of having only one branch.

199 SBPWS models are particular random *lacunary* wavelet series (Jaffard, 2000) based on
 200 simple branching processes. Lacunary refers to the property that only a small number of
 201 coefficients in the series are non-vanishing, more precisely those indexed by an elementary
 202 branching process and corresponding to the branches of Figure 6a. SBPWS is defined by:

$$203 \quad SBPWS(x) = \sum_{j=0}^{\infty} 2^{-jH} \sum_{i \in \Lambda(\mu)} \varepsilon_{j,i} \psi(2^j x - i) \quad (7)$$

204 where x is the spatial coordinate, H is the fractional parameter, $\Lambda(\mu)$ is the elementary
205 branching process of parameter μ , $\varepsilon_{j,i}$ are a family of independent Gaussian standard
206 random variables and ψ is a wavelet-like function.

207 Only wavelets with coefficients indexed by the stochastic sub-tree \mathcal{A} (of non-vanishing
208 coefficients) contribute to the roughening of the initial flat profile (see [Figure 6b](#)).
209 Therefore, the stochastic tree process \mathcal{A} locally deforms the 1D profile, at all the tree
210 branches.

211 In this model, elementary forms of the deformation are given by the shape of the mother-
212 function ψ . A difficulty with modeling a stylolitic structure is to choose the function ψ ,
213 which corresponds to the shape of each dissolution increment. However, it has been shown
214 that the statistics of a simulated signal do not depend on the shape of ψ , as long as this
215 function has the same property as an individual wavelet ([Brouste, 2006](#)).

216 In nature, the stylolite shape varies from columnar to conical ([Figures 1, 4](#)) and these two
217 kinds of shape might be related to the shape of microscopic increment of dissolution: either
218 rectangular for columnar stylolites, or triangular for the conical ones. As a consequence, a
219 choice must be made in the mathematical modeling between rectangular or triangular
220 increments or a specific parameter used that may express all the intermediary shapes.
221 Moreover, columnar stylolites are rather specific, being associated either with
222 microfractures ([Figure 4d and 4e](#)) or with non-consolidated material ([Gratier et al., 2005](#)).
223 In order to avoid the use of a third parameter, the shape of the function ψ , which might
224 hide the effect of the two other parameters, a triangular function was chosen for ψ ([Figure](#)
225 [6b, inset](#)). Note that the choice of the shape of this function ψ does not modify the
226 statistical properties of the synthetic signal.

227 The natural stylolites that were examined in this study can be modeled with such an
228 elementary triangular shape. By varying the parameters H and μ , one can generate synthetic
229 profiles that have stylolite-like patterns (Figure 7; Appendix A gives the algorithm to build
230 these synthetic stylolites). These synthetic profiles, unlike those generated by previous
231 models, exhibit two important properties of the natural stylolites:

- 232 i) the variability of the roughness between independent stylolite profiles;
233 ii) the variability of the roughness within a single profile, with alternating regular and
234 irregular portions.

235 3.3. Parameters H and μ

236 The parameters H and μ have distinct visual effects on the synthetic profiles. The
237 irregularities on the whole profile are quantified by the parameter μ : for instance, at the n^{th}
238 order branches, there are, on average, μ^n non-vanishing coefficients and then μ^n branches
239 of the tree, corresponding to μ^n stages of deformation of the initially flat profile. When
240 μ is close to 2, there are irregularities everywhere along the profile. When μ decreases to 1,
241 there are alternating irregular and regular portions along the profile. Finally, when μ is
242 equal to 1, there are no more irregularities along the signal.

243 The amplitude of the deformation (only where it is deformed) depends on the scale, on a
244 random Gaussian variable, and on a fractional exponent H that can be considered to be a
245 local roughness parameter. In this sense, H is indicative of the nature of the irregularity and
246 the amplitude of the profile variations. When H tends to 0 the profile is irregular and looks
247 “noisy”. This property is also called antipersistence: locally a valley in the signal has a
248 greater probability of being followed by a hill. When H is close to 1, the profile roughness
249 is smoother and a valley or a hill in the signal tends to extend locally. This property is
250 called persistence (Meakin, 1998).

251 *3.4. Measurements of H and μ on a 1D data set*

252 As stated previously, the SBPWS have scaling properties that no longer involve a unique
 253 stationary Hurst exponent. SBPWS provides self-affine behavior either in the 1D Average
 254 Wavelet Coefficient technique or in the Fourier Power Spectrum, and is defined by a
 255 power-law in both scale and frequency domains, respectively (Brouste, 2006):

256
$$AWC(l) \propto l^{1 - \log_2 \mu / 2 + H} \quad (8)$$

257 and

258
$$FPS(k) \propto k^{-2 + \log_2 \mu - 2H} \quad (9)$$

259 where H and μ are the two parameters of the SBPWS method. When $\mu = 2$, equations (8)
 260 and (9) are reduced to the Gaussian stationary case described in equations (4) and (6).

261 Note that in the SBPWS method, the values of H and μ cannot be determined by a simple
 262 regression to the 1D Fourier and AWC spectra, as done previously by Renard et al. (2004),
 263 because the following system of equations, whose determinant is equal to zero, is
 264 underdetermined:

265
$$\begin{cases} 2H - 2 + \log_2 \mu = a \\ H - 1 + \log_2 \mu / 2 = b \end{cases} \quad (10)$$

266 Here a and b are the slopes measured by linear regression on the FPS spectrum and on the
 267 AWC spectrum, respectively.

268 Therefore, a more complex tool must be used, such as the s-generalized variations method
 269 (Istas and Lang, 1997) to obtain estimated values of H and μ at large and small length
 270 scales. This method, detailed in Appendix B, was applied to estimate H and μ in the
 271 stylolites that were measured (Table 1).

272 **4. Application to natural stylolites**

273 *4.1. Parameters H and μ for the stylolites*

274 To estimate the parameters μ and H , from both sides of the cross-over length scale, it is
275 necessary to observe how the estimators of Appendix B behave when the length scale
276 decreases (as n increases), from large scales to small scales through the cross-over length
277 scale (Figure 8a-b). Large length scales values are taken at the cross-over length scale and
278 small ones are taken at the discretization scale in order to use the greatest number of points
279 in the two different patterns.

280 The results presented in Table 1 are based on averaged estimations of a series of 256 to 512
281 parallel stylolite profiles, each profile being regularly discretized on 512 to 1024 points.
282 This gives the large length scale and the small length scale parameters H and μ for all the
283 stylolites that have been measured.

284 4.2. Geometrical characterization

285 Most of the information on μ and H variability belongs to the large length scale parameters
286 (see Table 1). In fact, small length scale parameters have almost similar values (μ from 1.2
287 to 1.4 and H from 0.6 to 0.85) for all samples except S12A and S13A. These results are also
288 found on experimental microstylolites in quartz (Sdiss1 and Sdiss2 in Table 1, Gratier et al.,
289 2005), suggesting that an physical process smoothes the stylolites at small wavelengths.

290 Plotting the results of the analysis in μ versus H space, one can distinguish between two
291 classes of stylolites at long wavelengths. (Figure 10). A first class, called homogeneous
292 stylolites, contains two kinds of profile: i) the almost-everywhere irregular stylolites
293 (Sjura1 or S12A) and ii) the smooth stylolites (S11C or S10A). For both kinds, the
294 parameter μ is close to 2 (greater than 1.75), which represents few heterogeneities in the
295 rock. Irregular stylolites have a localized roughness parameter H that varies around 0.5 (0.4
296 to 0.5 in the results obtained here), contrary to smooth stylolites where H is close to 1.
297 Stylolites of this class can be simulated by dynamic surface growth models such as the

298 Langevin growth equations (Renard et al., 2004; Schmittbuhl et al., 2004) because profiles
299 have the same kind of irregularity almost everywhere.

300 The second class of stylolites, called heterogeneous stylolites, contains a variety of
301 morphologies. In this case the parameter μ is close to 1.5 (stylolites S3b or S0_8). These
302 stylolites are non-stationary. In this case, the initial heterogeneities in the rock that are
303 reached by the stylolite during its propagation are recorded in the stylolitic signal. More
304 exactly, above the millimeter scale, where elastic interactions dominate, heterogeneity may
305 be seen in the signal. Below the millimeter scale, where surface tension dominates, this
306 heterogeneity has disappeared.

307 Agglomerative nesting, clustering methods and principal component analysis (not shown
308 here) have been performed and indeed show that statistical analysis supports the
309 classification of stylolite morphologies in two different classes.

310 *4.3. Simulations*

311 Given a set of parameters (H, μ) for both regimes (large and small length scale behaviors
312 from both parts of the cross-over length scale), the behavior of all measured stylolites can
313 be reproduced with two SBPWS. This technique can be used to simulate a wide range of
314 stylolite morphologies (Figures 7, 9):

- 315 - those which are close to stationary profiles (μ close to 2);
- 316 - smooth profiles with H close to 1 to irregular profiles with a fractional exponent H ;
- 317 - more heterogeneous profiles with alternating smooth and irregular zones (where $\mu \neq 2$).

318 An interesting perspective would be to use the shape and regularity of stylolites in order to
319 evaluate the heterogeneity of the rock before or during the stylolitic process, and therefore
320 better characterize under which conditions (depth, cohesion of the sediment) stylolites
321 form. Another perspective would be to choose a different noise (a fractional stable noise for

322 instance) in the Langevin growth equations proposed in [Renard *et al.* \(2004\)](#) and
323 [Schmittbuhl *et al.* \(2004\)](#). This remains a real prospect for continuous stylolites models and,
324 more generally, a theoretical extension of rough surface growth models.

325 **4. Conclusion**

326 When the increments of a mathematical function are not stationary (in other words their
327 statistics vary along the coordinate), or the variance of their distribution is infinite, standard
328 tools (Fourier spectrum or average wavelet coefficient analysis) fail to capture a roughness
329 property from a scaling property.

330 Therefore, an extension of such tools to non stationary signals is proposed here by using a
331 two-parameter approach. One of the parameters, the local roughness exponent H , describes
332 the noisiness or waviness of the signal. The second parameter, μ , describes how the
333 statistical properties vary along the signal.

334 Applied to stylolites, two kinds of geometry can be distinguished.

335 i) Stationary stylolites, where the statistics do not vary along the stylolite. For this kind of
336 stylolite, two sub-families can be defined: stylolites that are almost flat everywhere and
337 those that are very wavy everywhere.

338 ii) Non-stationary stylolites where wavy portions alternate with flatter ones. In this case, we
339 propose that heterogeneities initially present in the rock strongly control the stylolite
340 morphology. To our knowledge, this second kind of stylolite, which has fossilized the
341 heterogeneities of the rock in its morphology, has not been previously quantified. Detailed
342 microstructural and chemical mapping studies focusing on the characterization of
343 heterogeneities around stylolites would surely bring new information.

344 This difference between the two families of stylolites is detected only for wavelengths
345 greater than a crossover scale close to the millimeter. Below this scale, the statistics of all

346 the stylolites are very homogeneous, indicating that a physical process, probably driven by
347 the minimization of the local curvature, smoothes the stylolites at small scales.

348

349 **Acknowledgments**

350 This project was supported by the CNRS (ATI and DyETI programs).

351

352 **Appendix A: Algorithm to build synthetic signals**

```

353 %////////// Run the styloprocess function ////////////
354 %Matlab© program to create the stylolites of Figure 7
355 %Parameters of the simulation
356 %K: depth of the tree (2^K+1 is the number of points on the
357 profile)
358 %mu: heterogeneity parameter (between 1 and 2)
359 %H: local roughness exponent (between 0 and 1)
360
361 function (stylolite) = styloprocess (K,mu,H)
362
363 x=linspace(0,2,2^(K-1));
364 y=1-abs(x-1);
365 psi=(-y,y,0);
366 trees=createtree(K,(2-mu));
367 profile=reconstruct(K,trees,H,psi);
368 plot(surface);
369
370 %////////// Galton-Watson Tree ////////////
371 function (trees)=createtree(K,p)
372
373 randn('state',sum(100*clock));
374 trees(1)=randn(1);
375 for m=0:K-1
376     for l=0:2^m-1
377         zfather=2^m+l;
378         zson1=2*zfather;
379         zson2=2*zfather+1;
380         if (trees(zfather)==0)
381             trees(zson1)=0;
382             trees(zson2)=0;
383         else
384             if (rand(1)<p)
385                 if (rand(1)<1/2)
386                     trees(zson1)=randn(1);
387                     trees(zson2)=0;
388                 else
389                     trees(zson2)=randn(1);
390                     trees(zson1)=0;
391                 end
392             else
393                 trees(zson1)=randn(1);
394                 trees(zson2)=randn(1);
395             end
396         end
397     end
398 end
399

```

```

400 %//////////////////// Reconstruction //////////////////////
401 function (sig)=reconstruct(K,trees,H,psi)
402
403 sig=zeros((1, 2^K+1));
404 for m=0:K
405     psim=();
406     for j=1:2^(K-m)+1
407         psim(j)=2^(m/2)*psi(2^(m)*(j-1)+1);
408     end
409     sigtemp=(0);
410     for l=0:2^m-1;
411         zfather=2^m+l;
412         psitemp=2^(-m*(H+1/2))*trees(zfather)*psim;
413         sigtemp=(sigtemp,psitemp(2:2^(K-m)+1));
414     end
415     sig=sig+sigtemp;
416 end

```

417 **Appendix B: Calculation of H and μ on 1D signals**

418 A 1-D profile $h(x)$ is observed on a regular grid (at space $x_i = i/2^n$ for $i = 0 \dots 2^n - 3$).

419 Note the second order variation, an approximation of the second order derivative, at

420 point x_i , by

$$421 \quad \Delta_a h\left(\frac{i}{2^n}\right) = \sum_{l=0}^2 a_l h\left(\frac{i+l}{2^n}\right) \quad (\text{B1})$$

422 where $a = (a_0, a_1, a_2) = (-1, 2, -1)$.

423 Summing the $2^n - 3$ variations $\Delta_a h(i/2^n)$ for $i = 0 \dots 2^n - 3$, the statistic $V_{n,s}$ is obtained:

$$424 \quad V_{n,s} = \sum_{i=0}^{2^n-3} \left(\Delta_a h\left(\frac{i}{2^n}\right) \right)^s \quad (\text{B2})$$

425 where $s = 2$ (also called quadratic variations) or $s = 4$ (quadric variations). This statistics

426 behave according to a power law depending on the parameters H and μ , with

$$427 \quad V_{n,s} \approx 2^{n(sH - \log_2 \mu)}.$$

428 If we note,

429
$$W_{n,s} = \log_2 \left(\frac{V_{n-1,s}}{V_{n,s}} \right) \quad (\text{B3})$$

430 then $W_{n,s} \xrightarrow{n \rightarrow \infty} sH - \log_2 \mu$ and by linear combination, either μ or H is obtained. The

431 estimators are respectively:

432
$$\mu_n = 2^{2W_{n,2} - W_{n,4}} \text{ and } H_n = \frac{1}{2}(W_{n,4} - W_{n,2}). \quad (\text{B4})$$

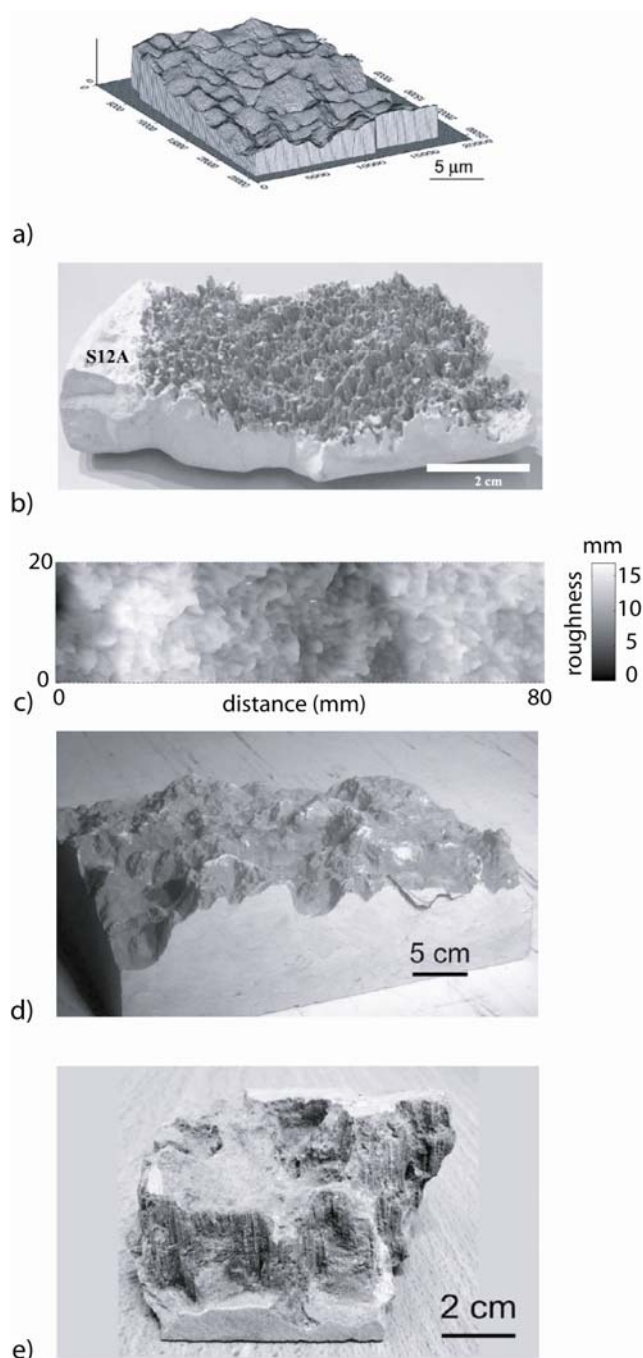
433

434 **References**

- 435 Barabási, A. L. and Stanley, E. H., 1995. Fractal concepts in surface growth. Cambridge
436 University Press. New York.
- 437 Bathurst, R. 1971. Carbonate sediments and their diagenesis. Elsevier Science, New York.
- 438 Bayly, B. 1986. Mechanisms for development of stylolites. *Journal of Geology* 94, 431-
439 435.
- 440 Brouste, A. 2006. Simple Branching Process Wavelet Series, submitted to *Journal of*
441 *Theoretical Probability*.
- 442 Cerasi, P, Mills, P., and Fautrat, S., 1995. Erosion instability in a non consolidated porous
443 medium. *Europhysics Letters* 29, 215-220.
- 444 Daubechies, I., 1992. Ten Lectures on Wavelets. Society for Industrial and Applied
445 Mathematics, Philadelphia.
- 446 Dunne, T., 1980. Formation and controls of channel networks. *Progress in Physical*
447 *Geography* 4, 211-239.
- 448 Dunnington, H., 1954. Stylolites development post-date rock induration. *Journal of*
449 *Sedimentary Petrology* 24, 27-49.
- 450 Feder, J., 1988. Fractals. Plenum Press.
- 451 Fletcher, R. A., and Pollard, D. D., 1981. Anticrack model for pressure solution surfaces.
452 *Geology* 9, 419-424.
- 453 Gratier, J., Muquet, L., Hassani, R. and Renard, F., 2005. Experimental microstylolites in
454 quartz and modeled application to natural stylolitic structures. *Journal of Structural*
455 *Geology* 27, 89-100.
- 456 Harris, T.E., 1963. The Theory of Branching Processes. Springer-Verlag, Berlin.

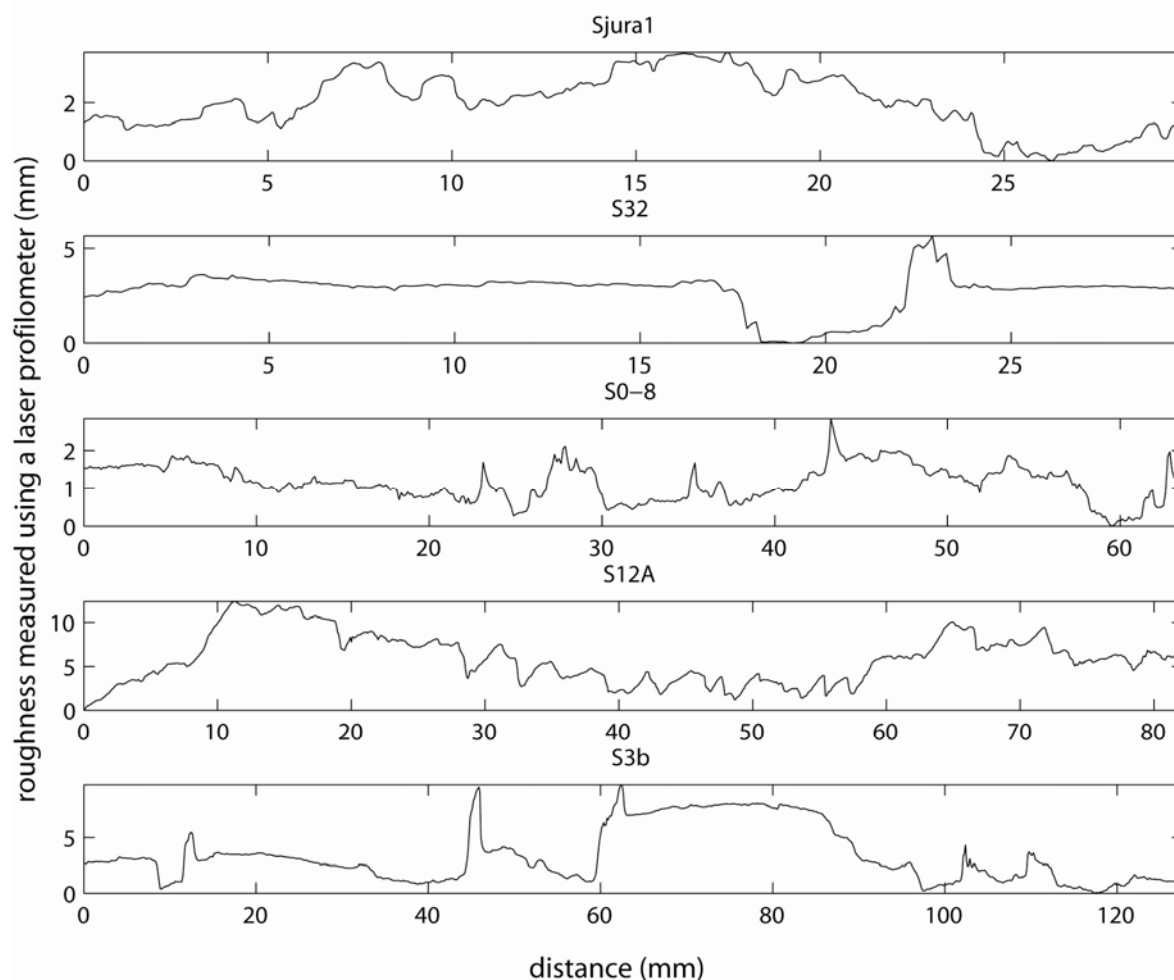
- 457 Istas, J., and Lang, G., 1997. Quadratic variations and estimation of the local Hölder index
458 of a Gaussian process. *Annales Institut Henri Poincaré* 33(4), 407-436.
- 459 Jaffard, S., 2000. On Lacunary Wavelet Series. *Annales Institut Henri Poincaré* 10, 313-
460 329.
- 461 Kahane, J. P., and Lemarié-Rieusset, P. G., 1998. *Séries de Fourier et ondelettes*. Editions
462 Cassini, Paris.
- 463 Karcz, Z., and Scholz, C. H., 2003. The fractal geometry of some stylolites from the
464 Calcare Massiccio Formation, Italy. *Journal of Structural Geology* 25, 1301-1316.
- 465 Katsman, R., Aharonov, E., and Scher, H., 2006. A numerical study on localized volume
466 reduction in elastic media: some insights on the mechanics of anticracks. *Journal of*
467 *Geophysical Research* 111, B03204. doi:10.1029/2004JB003607.
- 468 Koehn, D., Arnold, J., Malthe-Sorrensen, A., and Jamtveit, B., 2003. Instabilities in stress
469 corrosion and the transition to brittle failure. *American Journal of Science* 303, 956-971.
- 470 Meakin, P., 1998. *Fractals: scaling and growth far from equilibrium*. Cambridge University
471 Press, New York.
- 472 Meyer, Y., and Roques, S., 1993. Progress in wavelets analysis and applications. In:
473 *Proceedings of the International Conference "Wavelets and Applications"*, Editions
474 Frontières.
- 475 Park, W. and Schot, E., 1968. Stylolites: their nature and origin. *Journal of Sedimentary*
476 *Petrology* 38, 175-191.
- 477 Samorodnitsky, G. and Taqqu, M. S., 1994. *Stable Non-Gaussian Random Processes:*
478 *Stochastic models with infinite variance*. Chapman and Hall, New-York.
- 479 Schmittbuhl, J., Gentier, S., and Roux, S., 1993. Field measurements of the roughness of
480 fault surfaces. *Geophysical Research Letters* 20, 639-641.

- 481 Schmittbuhl, J., Renard, F., Gratier, J.-P., Toussaint, R., 2004. The roughness of stylolites:
482 Implications of 3D high resolution topography measurements. *Physical Review Letters* 93,
483 238501.
- 484 Simonsen, I., Hansen, A., and Nes, O.M., 1998. Using wavelet transforms for Hurst
485 exponent determination. *Physical Review E* 58, 2779-2787.
- 486 Renard, F., Schmittbuhl, J., Gratier, J.-P., Meakin, P., and Merino, E., 2004. Three-
487 dimensional roughness of stylolites in limestones. *Journal of Geophysical Research* 109,
488 B03209. doi:10.1029/2003JB002555.
- 489 Rubio, M. A., Edwards, C. A., Dougherty, A., and Gollub, J. P., 1989. Self-affine fractal
490 interface from immiscible displacement in porous media. *Physical Review Letters* 63,
491 1685-1688.
- 492

493 **Figures & Table**

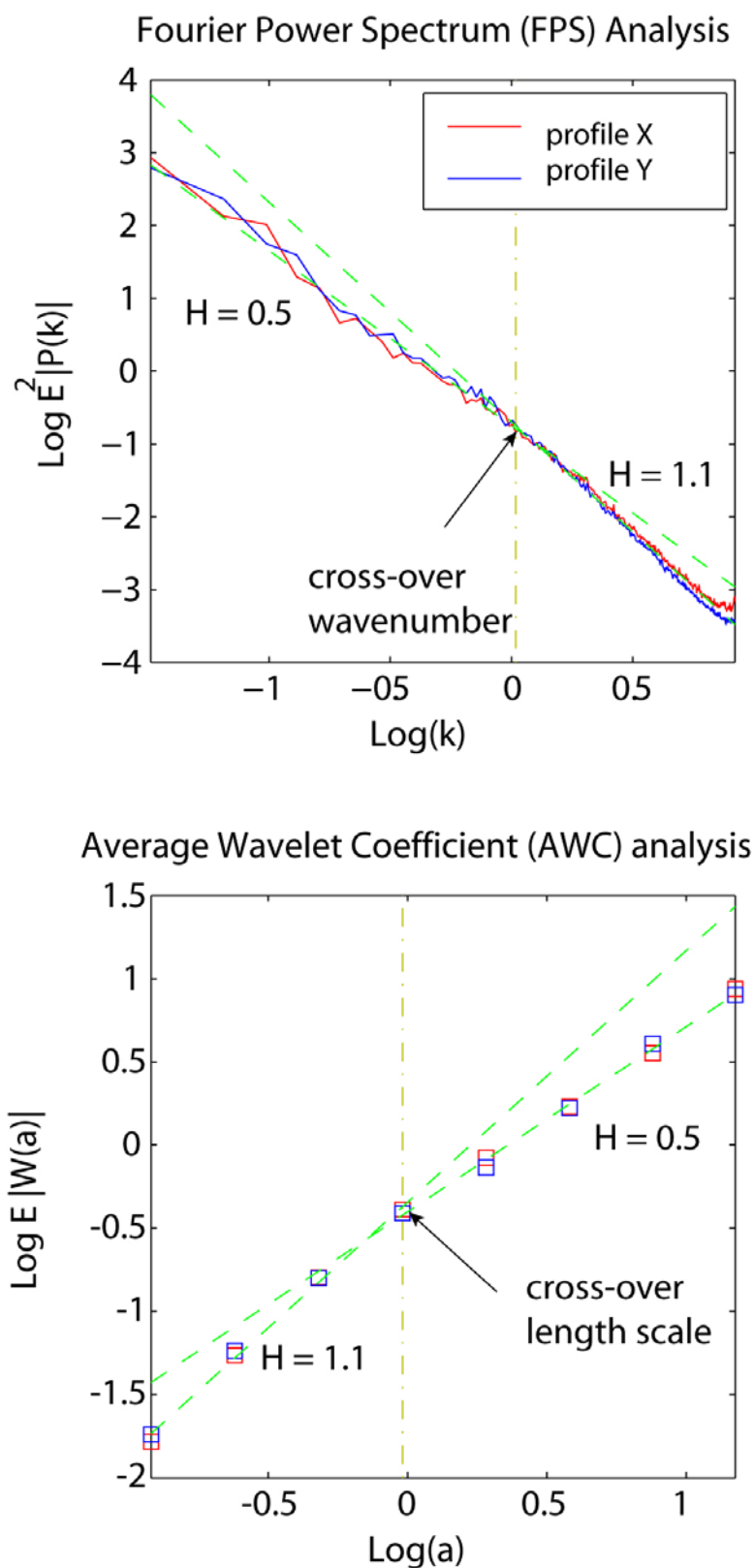
494
 495
 496
 497
 498
 499
 500
 501
 502
 503

Figure 1. Various shapes of stylolites. a) Digital elevation model of a microstylolites measured at the contact between experimentally deformed quartz grains (after Gratier et al., 2005, isotropic scale). b) 2D stylolite surface S12A in a limestone. c) Roughness field of the surface S12A measured using a laser profilometer (Renard et al., 2004). d) Stylolite S3b showing local variations in roughness, with alternating smooth and rougher areas. Such lateral roughness variations are a good visual indicator that the roughness statistics are not the same all along the profiles. e) Stylolite in limestone with vertical peaks showing strong lateral variations in height. It was not possible to measure the roughness of such stylolites because of local overhangs.



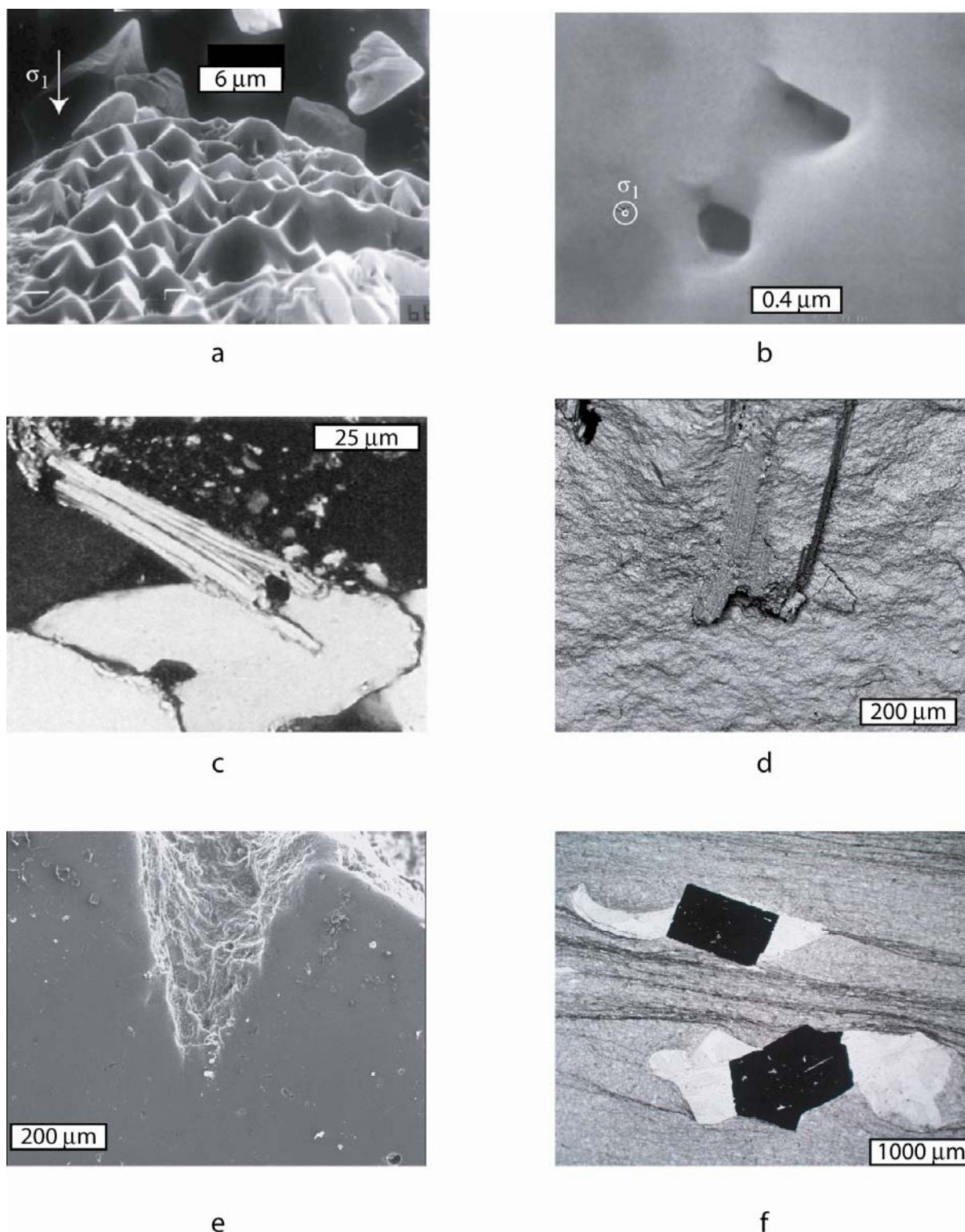
504
 505
 506
 507
 508
 509
 510
 511

Figure 2. Examples of the 1D roughness of different stylolites in limestones measured using laser profilometer (see Renard et al. (2004) for the measurement technique). The waviness of the stylolite, characterized by the Hurst exponent H varies from sample to sample. Moreover, within the same stylolite, regions with smooth or wavy roughness can be defined, and characterized by the amount of irregularities defined by the parameter μ (see text). Scales are given in mm. The characteristics of each profile are given in Table 1.



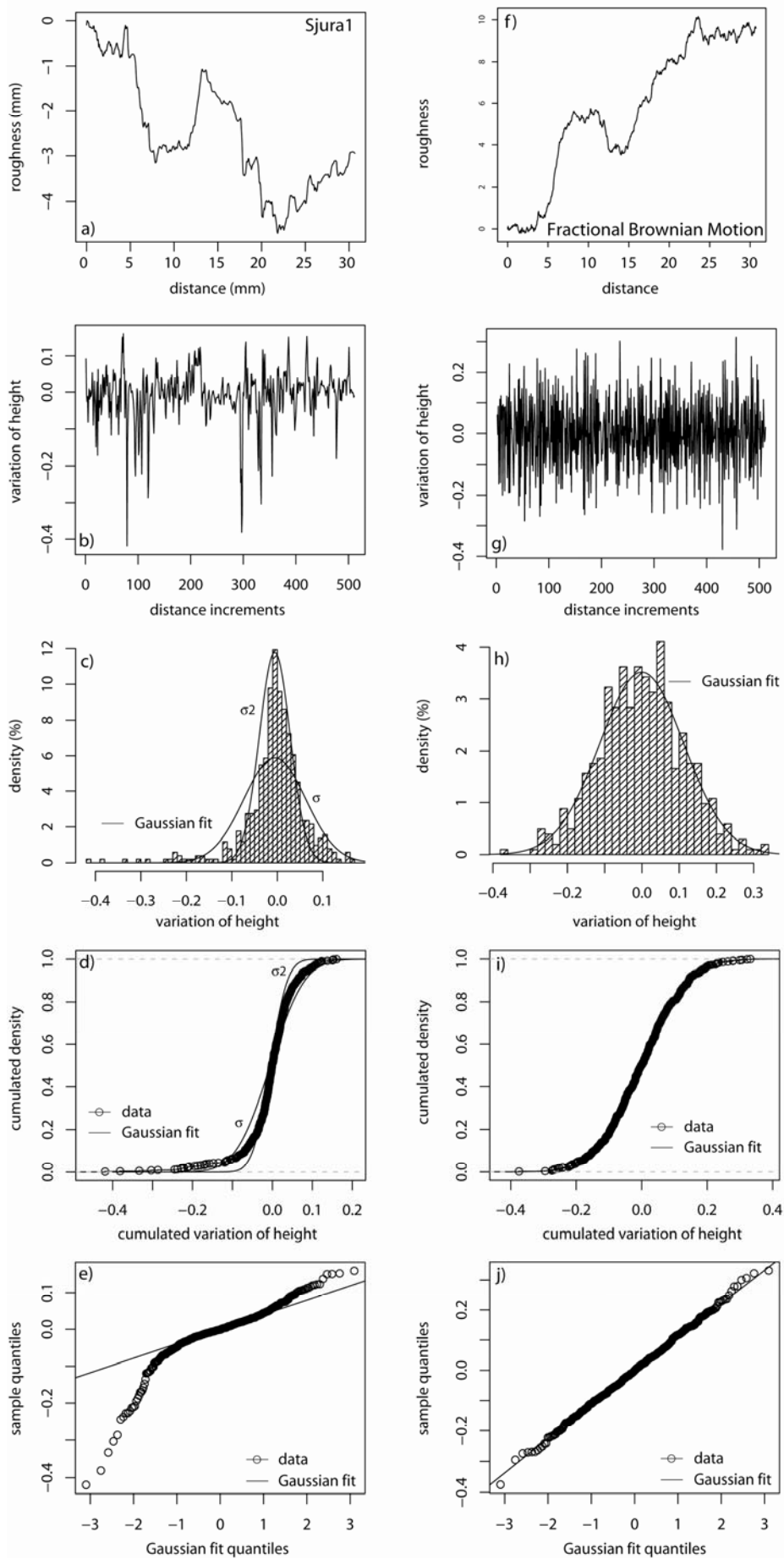
512

513 **Figure 3.** FPS (top) and AWC (bottom) for the stylolite Sjura1. These two independent514 scaling methods show that there is a crossover at $\sim 1\text{mm}$ between the small wavelengths515 ($H \sim 1.1$) and the large wavelengths ($H \sim 1.5$).



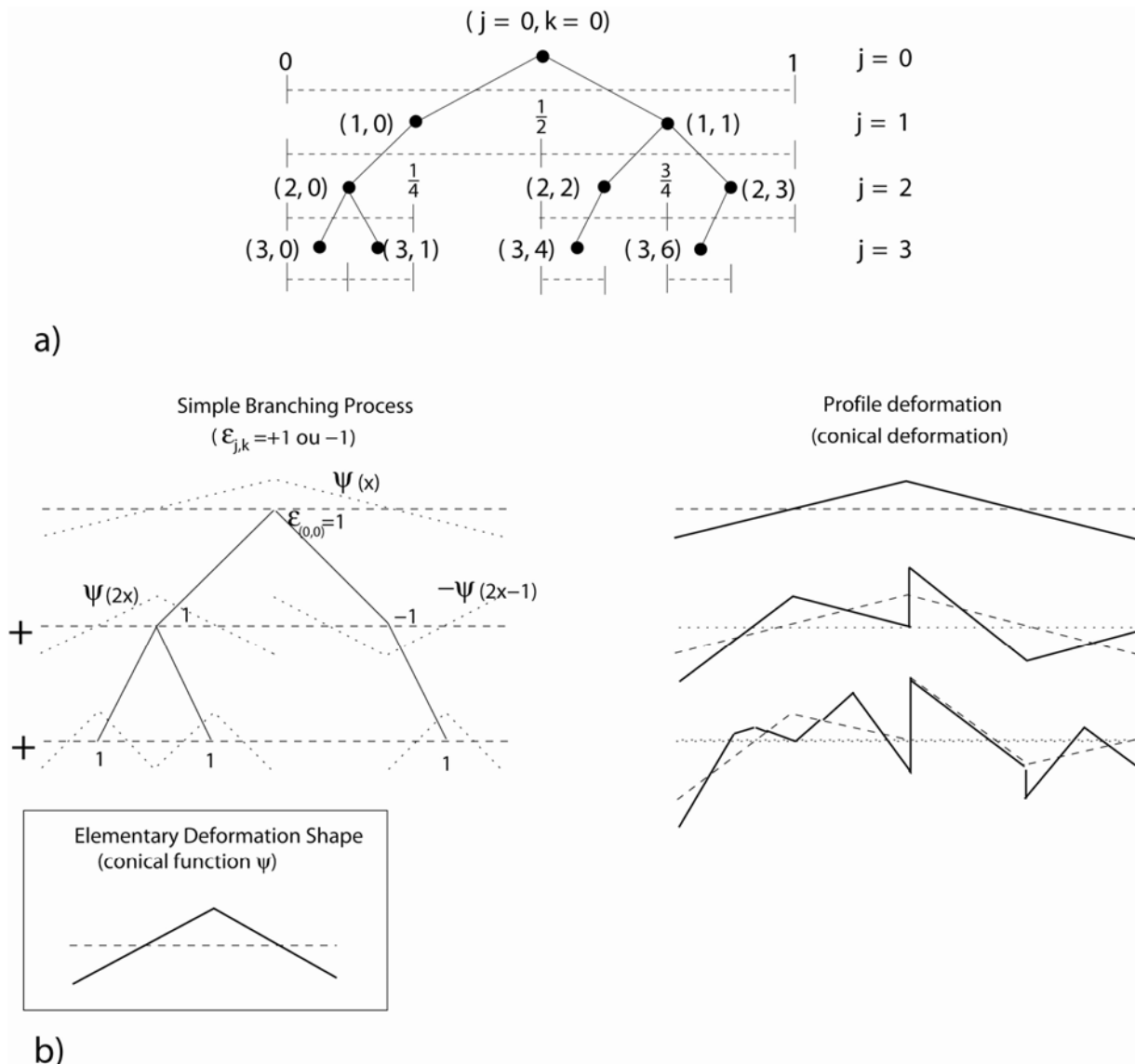
516
517
518
519
520
521
522
523

Figure 4. Heterogeneities associated with stylolites. a-b) Microstylolite on a quartz grain (Gratier et al., 2005) and zoom on two dislocation pits where deformation is localized. c) Mica indenting a quartz grain in a North Sea Sandstone and showing a wavy interface at the grain scale. d-e) Zoom on stylolite peaks in the sample Sjura1. f) Dissolution seams (“flat” stylolites) deflected by pyrite crystals and quartz pressure shadows in a metamorphic schist from Bourg d’Oisans (Alps, France).



525 **Figure 5.** a) Laser roughness measurement of a 1D profile from the stylolite Sjura1. b)
526 Local increments of the stylolite Sjura1, corresponding to the first order discrete derivative
527 of profile a). c) Histogram of the increments of b) with the best Gaussian fits represented by
528 the two curves, which have the same standard deviation (σ) and half the standard deviation
529 ($\sigma/2$) of the stylolite data. d) Cumulative distribution function of b). The two lines represent
530 the best Gaussian fits as in b). The large jumps of the local increments and the long tails in
531 the histogram cannot be accounted for using Gaussian stationary statistics (plain curves). e)
532 Quantile-quantile plot that adjusts the sample distribution in d) against the best Gaussian
533 distribution. This corresponds to the difference between the data and the Gaussian estimate
534 of d). For a Gaussian distribution a straight line should be observed. f -j) Same plots for a
535 synthetic fractional Brownian motion. In the quantile-quantile plot, the synthetic signal and
536 the Gaussian best fit adjust perfectly on a straight line, showing that the fractional
537 Brownian motion is a Gaussian stationary increments signal.
538

539



540

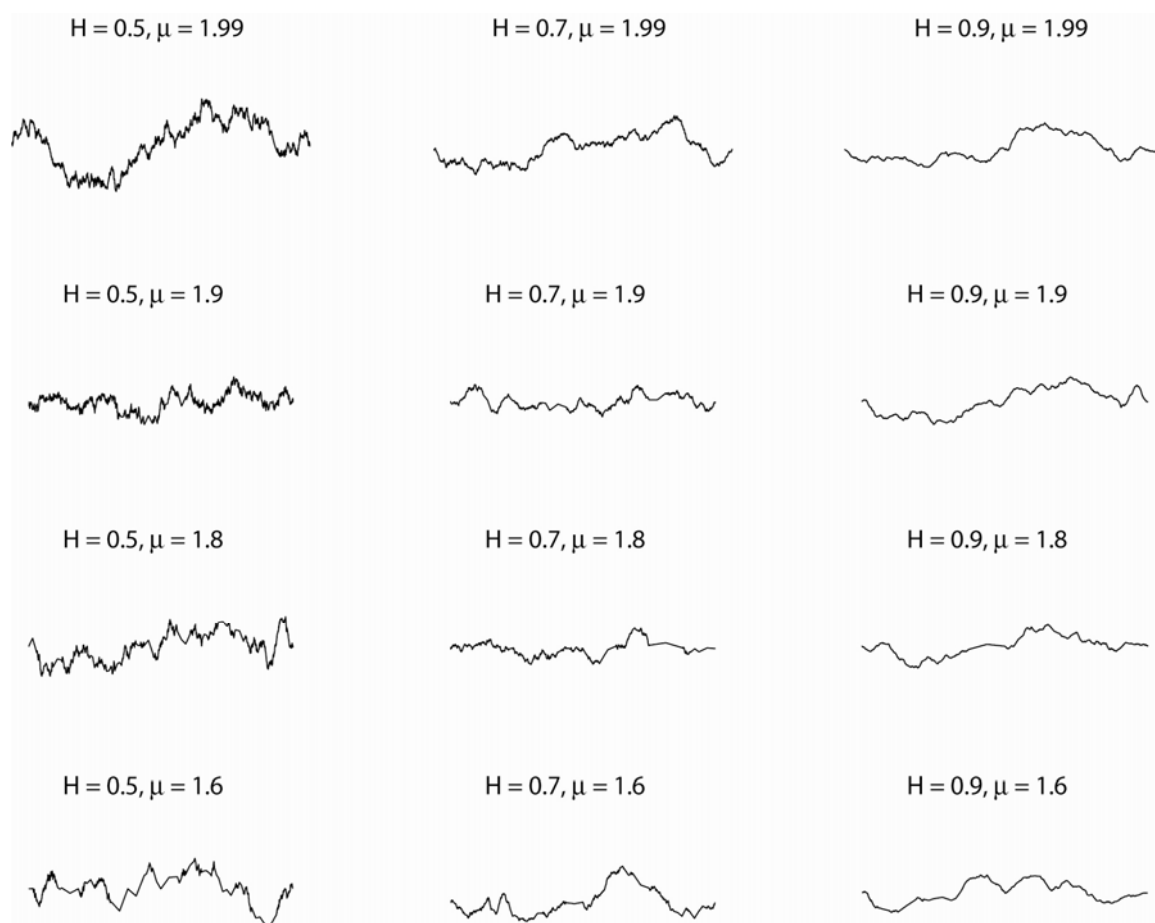
541

542

543

544

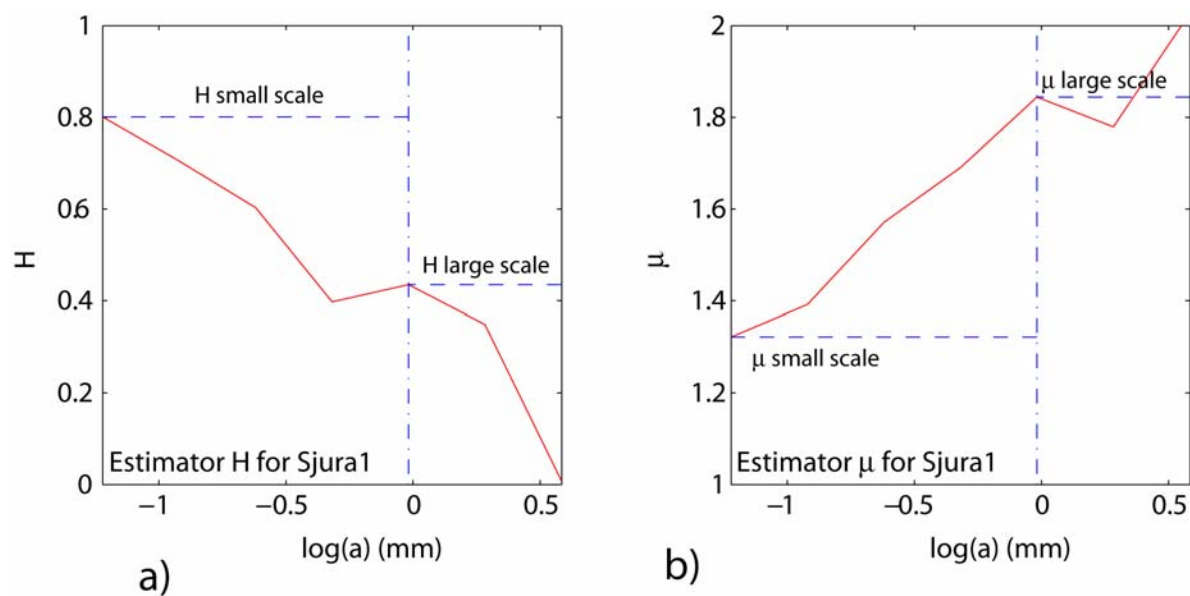
Figure 6. a) Galton-Watson tree (simple branching process) and indexes for the wavelet construction. b) Construction of a synthetic 1D profile using the branching process wavelet series. Such technique is used to build the synthetic signals of Figure 7, using the algorithm given in Appendix A.



545
546
547
548
549
550
551

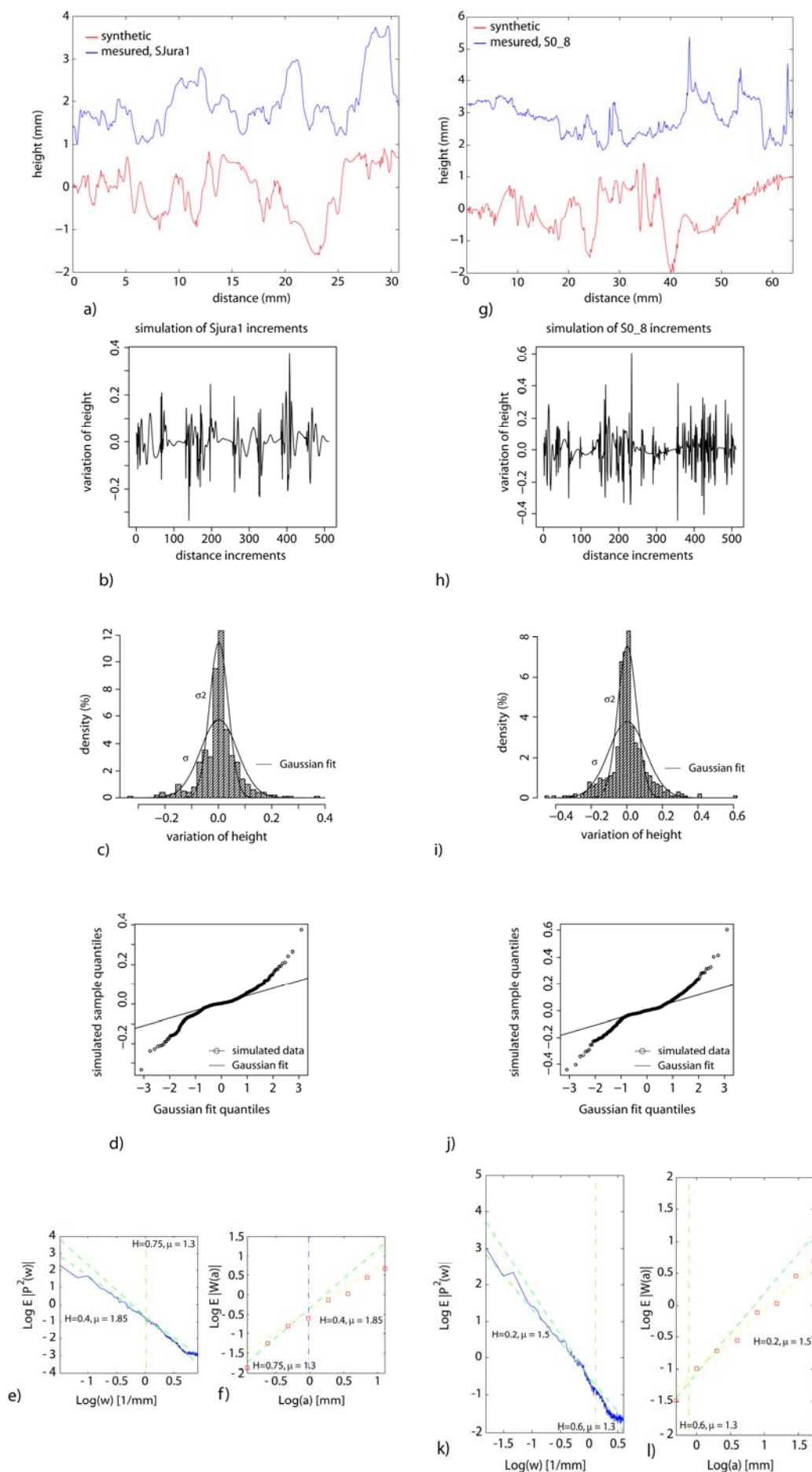
Figure 7. Simulated stylolites with statistical roughness properties characterized by two parameters. The variability in the stylolite morphology is controlled by H which describes the apparent noisiness (smoothness) of the roughness, and μ which describes the spatial variability (heterogeneities at all scales) along the stylolite.

552
553



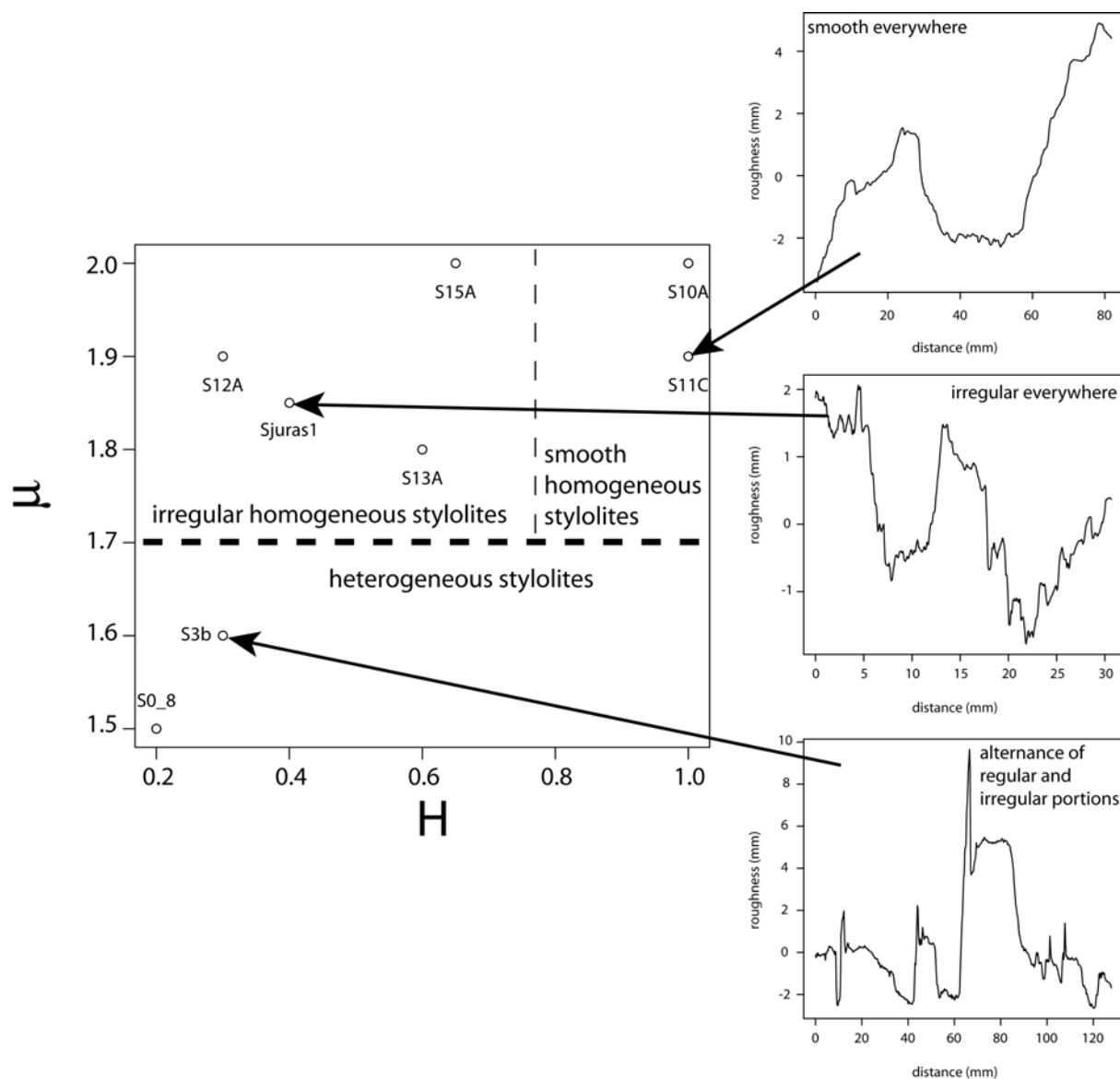
554
555
556
557
558
559
560

Figure 8. a, b) Estimators of μ and H for the stylolite Sjura1 at small length scales and large length scale. As the length-scale a decreases (n increases in the equations of Appendix B, where n represents the level of branching in Figure 6), the estimated values converge respectively to H and μ just above the cross-over length scale for large length scales and as allowed by the precision for small length scales.



562 **Figure 9.** Using both values H and μ estimated at large length scale and at small length
563 scale, one can reproduce different morphologies of stylolites using a combination of two
564 SBPWS behaviors. a) Profile of the stylolite Sjura1 (see Table 1) and synthetic profile with
565 the same parameters at small and large length scales as those estimated on Sjura1. b)
566 Derivative of the synthetic signal of a) showing the increments. c) Histogram of the
567 simulated increments. d) Quantile-quantile plot, as in figure 5 showing the departure from a
568 Gaussian distribution. FPS (e) and AWC (f) spectra analysis for the synthetic signal having
569 the same statistical properties as Sjura1. The green dashed straight lines at small and large
570 length scales indicate the estimated slopes, showing the two characteristic slopes and the
571 crossover length scale. g-l) Stylolite S0_8 and synthetic profiles with the same parameters
572 as estimated on S0_8 and similar analysis than in a-d). FPS (g) and AWC (h) spectra of the
573 synthetic stylolite showing the two characteristic slopes and the crossover length scale.
574

575



576
 577
 578
 579
 580
 581

Figure 10. Various morphologies of stylolites based on their statistical properties at large length scale. Two main families can be identified, based on their statistical properties: those which are either regular or irregular everywhere, and those with alternating regular and irregular portions.

582 **Table 1.** Large and small length scale scaling exponents of the various stylolites.

stylolite	origin	H_{small}	μ_{small}	H_{large}	μ_{large}
Sjura1	Jura mountains	0.75	1.3	0.4	1.85
S12A	Vercors mountains	0.2	1	0.3	1.9
S11c	Burgundy mountains	0.7	1.35	1	1.9
S3b	Chartreuse mountains	0.5	1.4	0.3	1.6
S15A	Burgundy	0.6	1.4	0.65	2
S0_8	Jura mountains	0.6	1.3	0.2	1.5
S13A	Burgundy	0.9	1.8	0.55	1.8
S10A	Burgundy	0.85	1.4	1	2
Sdiss1	Experimental microstylolite	0.8	1.25	-	-
Sdiss2	Experimental microstylolite	0.75	1.2	-	-

583 1 For more details on the geological characteristics and composition of the stylolites, see Renard et al. (2004)

584 and Gratier et al. (2005) for the experimental microstylolites.